Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination
10/780,148	KAISE ET AL.
Examiner	Art Unit
Binh X. Tran	1765

SEARCHED					
Class	Subclass	Date	Examiner		
216	24	3/27/2006	вт		
216	26	3/27/2006	ВТ		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
216	24	3/27/2006	ВТ	
216	26	3/27/2006	вт	
		•		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Updated search using	3/27/2006	ВТ